ADXL362W Sensor Wafer Site and Trim Transfer

Qualification Results Summary for ADXL362W Wafer Site & Trim Transfer

Qualification Results			
Test	**Specification**	**Sample Size**	**Results**
Temperature Cycling (TC) *	JESD22-A104	3 x 77	PASS
Temperature Humidity Storage (THS)*	JESD22-A101	3 x 77	PASS
Unbiased HAST (UHAST)*	JESD22-A118	3 x 77	PASS
Group D	MIL-STD-883, M5005	3 x 32	PASS
Mechanical Shock Unpowered	IEC 60068-2-27	3 x 32	PASS
Mechanical Shock Powered	IEC 60068-2-27	3 x 32	PASS
Random Drop	AEC-Q100 Test G5	3 x 35	PASS
Wire Bond Pull**	MIL STD 883 M2011	2 x 10	PASS

* These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: 1. Bake – 24 hours at 125ºC; 2. Soak – unbiased soak for 192 hours at 30ºC, 60%RH; 3. Reflow – three passes through a reflow oven with a peak temperature of 260ºC.

**TC samples were subjected to wire-pull test after 1000 cycles with results within specification limits.